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Advanced Technologies for Image/Video Quality Assessment

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Deadline for manuscript submissions:

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Message from the Guest Editors

Dear Colleagues,

Advanced technologies, such as deep neural networks and reinforcement learning strategies, have been designed and deployed in scientific and industrial fields. These technologies have boosted the performance of multimedia services and enhanced the quality of user experience.

This Special Issue will provide a forum to publish original research papers and review articles covering novel methodologies, applications, and theories of advanced technologies in image and video quality assessment, as well as related topics.

This Special Issue is primarily focused on, but not limited to, the following topics:

- 1. Image, medical image and video quality assessment;
- 2. Image, medical image and video quality enhancement:
- 3. Aesthetic evaluation;
- 4. Distortion detection and recovery;
- 5. Measuring quality of user experience;
- 6. Quality-guided optimization of image processing.

We look forward to receiving your contributions!!!



Specialsue







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Message from the Editor-in-Chief

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